Notice of References Cited Application/Control No. 10/559,846 Examiner Hae Moon Hyeon Applicant(s)/Patent Under Reexamination IGARASHI ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,870,385 B2	03-2005	Inoue et al.	324/765
	В	US-			
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			·
	Н	US-			
	Į	US-			
	J	US-			
	К	US			
- 1	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name ,	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)							
	υ								
	v								
	w		į						
	x								

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.